

IN THE ABSTRACT:

The Abstract as amended below shows added text with underlining and deleted text with ~~strikethrough~~.

Please DELETE the Abstract in its entirety and substitute the attached new/replacement Abstract.

An inspecting apparatus for ~~a semiconductor devices comprising:~~ device includes a match plate; a contact module combined with the match plate, ~~itself comprising and including~~ a radiator to radiate heat from the semiconductor device to the outside and a tester to contact the leads of the semiconductor device; and a heat pipe provided in the radiator. ~~Accordingly, the~~ The inspecting apparatus ~~for semiconductor devices according to the present invention~~ performs testing at a constant temperature, regardless of heat from the semiconductor device, by transferring the heat ~~from the semiconductor device~~ quickly and efficiently, thereby producing more accurate test results. ~~The inspecting apparatus for semiconductor devices according to the present invention~~ also improves productivity and saves expense by removing faulty test results caused by incorrectly identifying a qualified semiconductor devices device as a defective semiconductor devices device.

IN THE TITLE:

The Title as amended below shows added text with underlining and deleted text with ~~strikethrough~~.

~~INSPECTING APPARATUS FOR SEMICONDUCTOR DEVICE~~ HAVING A RADIATOR TO
RADIATE HEAT FROM A SEMICONDUCTOR DEVICE